

# Search Notes



Application/Control No.

10/542,394

Examiner

Tran N. Nguyen

Applicant(s)/Patent under  
Reexamination

FUJITA, KATSUFUSA

Art Unit

2834

## SEARCHED

Class	Subclass	Date	Examiner
310	216 217 254 261	7/1/06 ↓	Tran ↓
336	210 ↓ 212 219 234	7/4/06 ↓	Tran ↓
Update all above		12/12/06	Tran

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR